

Notice of References Cited

Application/Control No.

10/607,184

Applicant(s)/Patent Under
Reexamination
PATTON ET AL.

Examiner

Brian Q Le

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,393,976	02-1995	Koike, Hirotami	250/310
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kurihara et al. "Fabrication of Functional Probes for Near-field Optic Microscopy", Lasers and Electro-Optics, 1997 pages: 148-149.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.